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Attorney Docket No. 108298705US
Disclosure No. 02-1607.00/US**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
Form PTO-1449 (Modified)
(Use several sheets if necessary)**COMPLETE IF KNOWN**

Sheet	1	of	1
Application Number	10/665,219		
Confirmation Number	6284		
Filing Date	September 17, 2003		
First Named Inventor	Whonchee Lee		
Group Art Unit	3723		
Examiner Name	Dung V. Nguyen		
Attorney Docket No.	108298705US		

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	U.S. Patent or Application		Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		NUMBER	Kind Code (if known)			
dvw		5,624,300✓		Kishii et al.	04/29/1997	
		6,689,258✓	B1	Lansford et al.	02/10/2004	
↓		6,776,693✓	B2	Duboust et al.	08/17/2004	

EXAMINER

Dung V. Nguyen

DATE CONSIDERED

12-1-2004

*EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application(s).

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DVN	**	U.S. Application No. 09/651,779 ✓ (Atty. Docket No. 10829.8515US)		Moore	Filed 08/30/2000	
	**	U.S. Application No. 09/651,808 ✓		Chopra et al.	Filed 08/30/2000	
	**	U.S. Application No. 09/653,392 ✓		Chopra et al.	Filed 08/31/2000	
	**	U.S. Application No. 09/653,411 ✓		Lee et al.	Filed 08/31/2000	
	**	U.S. Application No. 10/230,463 ✓ (Atty. Docket No. 10829.8672US)		Lee et al.	Filed 08/29/2002	
	**	U.S. Application No. 10/230,602 ✓ (Atty. Docket No. 10829.8674US)		Chopra	Filed 08/29/2002	
	**	U.S. Application No. 10/230,628 ✓ (Atty. Docket No. 10829.8673US)		Lee et al.	Filed 08/29/2002	
		2001/0025976 ✓	A1	Lee	10/04/2001	
		2001/0036746 ✓	A1	Sato et al.	11/01/2001	
		2002/0025763 ✓	A1	Lee et al.	02/28/2002	
		2002/0025760 ✓	A1	Lee et al.	02/28/2002	
		2002/0025759 ✓	A1	Lee et al.	02/28/2002	
		2002/0052126	A1	Lee et al.	05/02/2002	
		2002/0070126 ✓	A1	Sato et al.	06/13/2002	
		2003/0054729 ✓	A1	Lee et al.	03/20/2003	
		2003/0109198 ✓	A1	Lee et al.	06/12/2003	

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		NUMBER	Kind Code (if known)			
DVN		2003/0129927 ✓	A1	Lee et al.	07/10/2003	
		2003/0226764 ✓	A1	Moore et al.	12/11/2003	
		2,315,695 ✓		Faust	04/06/1943	
		2,516,105 ✓		der Mateosian	07/25/1950	
		3,334,210 ✓		Williams et al.	08/01/1967	
		4,839,005 ✓		Katsumoto et al.	06/13/1989	
		5,244,534 ✓		Yu et al.	09/14/1993	
		5,300,155 ✓		Sandhu et al.	04/05/1994	
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		5,618,381 ✓		Doan et al.	04/08/1997	
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		5,807,165 ✓		Uzoh et al.	09/15/1998	
		5,840,629 ✓		Carpio	11/24/1998	
		5,846,398 ✓		Carpio	12/08/1998	
		5,863,307 ✓		Zhou et al.	01/26/1999	
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		5,911,619 ✓		Uzoh et al.	06/15/1999	
		5,930,699 ✓		Bhatia	07/27/1999	
		5,934,980 ✓		Koos et al.	08/10/1999	

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		NUMBER	Kind Code (if known)			
DVN		5,952,687 ✓		Kawakubo et al.	09/14/1999	
		5,954,975 ✓		Cadien et al.	09/21/1999	
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		5,972,792 ✓		Hudson	10/26/1999	
		5,993,637 ✓		Hisamatsu et al.	11/30/1999	
		6,001,730 ✓		Farkas et al.	12/14/1999	
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		6,068,787 ✓		Grumbine et al.	05/30/2000	
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		6,100,197 ✓		Hasegawa	08/08/2000	
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		6,103,628 ✓		Talieh	08/15/2000	
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dvw		6,117,781✓		Lukanc et al.	09/12/2000	
		6,121,152✓		Adams et al.	09/19/2000	
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		6,143,155✓		Adams et al.	11/07/2000	
		6,171,467✓	B1	Weihs et al.	01/09/2001	
		6,174,425✓	B1	Simpson et al.	01/16/2001	
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		6,180,947✓	B1	Stickel et al.	01/30/2001	
		6,187,651✓	B1	Oh	02/13/2001	
		6,196,899✓	B1	Chopra et al.	03/06/2001	
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		6,259,128✓	B1	Adler et al.	07/10/2001	
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		6,280,581✓	B1	Cheng	08/28/2001	
		6,287,974✓	B1	Miller	09/11/2001	
		6,299,741✓	B1	Sun et al.	10/09/2001	
		6,303,956✓	B1	Sandhu et al.	10/16/2001	
		6,313,038✓	B1	Chopra et al.	11/06/2001	
		6,328,632✓	B1	Chopra	12/11/2001	
		6,368,190✓	B1	Easter et al.	04/09/2002	


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DVN		6,379,223/	B1	Sun et al.	04/30/2002	
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Examiner Initials*	Cite No.	Foreign Patent or Application			Name of Patentee or Applicant of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T
		Office	NUMBER	Kind Code (if known)				
DVN	**	JP	2001077117/	A2, A3	Sony Corp.	03/23/2001		
	**	EP/	0459397	A1	Kabushiki Kaisha Toshiba	12/04/1991		
	**	WO✓	02/064314	A1	Speedfam-IPEC Corporation	08/22/2002		
	**	WO✓	00/26443	A2, A3	Nutool, Inc.	05/11/2000		
	**	WO✓	00/28586	A2, A3	Micron Technology, Inc.	05/18/2000		
	**	WO✓	00/32356	A1	Nutool, Inc.	06/08/2000		
	**	WO✓	00/59008	A2, A3	Nutool, Inc	10/05/2000		
	**	WO✓	00/59682	A1	Nutool, Inc	10/12/2000		

OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume issue number(s), publisher, city and/or country where published.		
DVN	**	ABOAF, J.A. and R.W. BROADIE, IBM Technical Disclosure Bulletin, Rounding of Square- Shape Holes in Silicon Wafers, Vol. 19, No. 8, p. 3042, January 1977, XP-002235690, NN 77013042. ✓		
	**	ATMI, Inc., adapted from a presentation at the Semicon West '99 Low Dielectric Materials Technology Conference, San Francisco, California, July 12, 1999, pp. 13-25. ✓		
	**	BASSOUS, E., IBM Technical Disclosure Bulletin, Low Temperature Methods for Rounding Silicon Nozzles, Vol. 20, No. 2, July 1977, pp. 810-811, XP-002235692, NN 7707810. ✓		
	**	BERNHARDT, A.F., CONTOLINI, R.J., MAYER, S.T., "Electrochemical Planarization for Multi-Level Metallization of Microcircuitry," <i>CircuiTree Journal</i> , Vol. 8, No. 10, pp. 38, 40, 42, 44, 46, and 48, Oct. 1995. ✓		

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dvw	**	D'HEURLE, F.M. and K.C. PARK, IBM Technical Disclosure Bulletin, Electrolytic Process for Metal Pattern Generation, Vol. 17, No. 1, pp. 271-272, June 1974, XP-002235691, NN 7406271. ✓	
	**	FRANKENTHAL, R.P. and EATON, D.H., "Electroetching of Platinum in the Titanium-Platinum-Gold Metallization on Silicon Integrated Circuits", <i>Journal of The Electrochemical Society</i> , Vol. 123, No. 5, pp. 703-706, May 1976. ✓	
	**	HUANG, C.S. et al., "A Novel UV Baking Process to Improve DUV Photoresist Hardness," pp. 135-138, Proceedings of the 1999 International Symposium on VLSI Technology, Systems, and Applications: Proceedings of Technical Papers: June 8-10, 1999, Taipei, Taiwan, Institute of Electrical and Electronics Engineers, Inc., September 1999. ✓	
	**	JUCHNIEWICZ, R. et al. "Influence of Pulsed Current of Platinised Titanium and Tantalum Anode Durability," International Congress on Metallic Corrosion, Proceedings - Volume 3, pp. 449-453, Toronto, June 3-7, 1984.	
	**	KONDO, S. et al., "Abrasive-Free Polishing for Copper Damascene Interconnection," <i>Journal of the Electrochemical Society</i> , Vol. 147, No. 10, pp. 3907-3913, The Electrochemical Society, Inc., Pennington, New Jersey, 2000. ✓	
	**	McGraw-Hill, <i>Concise Encyclopedia of Science & Technology</i> , Sybil P. Parker, Editor in Chief, Fourth Edition, p. 367, McGraw-Hill, New York, 1998. ✓	
	**	Micro Photonics, Inc., "CSM Nano Hardness Tester," 6 pages, retrieved from the Internet on July 29, 2002, < http://www.microphotonics.com/nht.html >.	
	**	Micro Photonics, Inc., CSM Application Bulletin, "Low-load Micro Scratch Tester (MST) for characterisation of thin polymer films," 3 pages, retrieved from the Internet on July 25, 2002, < http://www.microphotonics.com/mstABpoly.html >. ✓	
	**	PhysicsWorld, "Hard Materials", excerpt of "Superhard Superlattices," 1 page, January 1998, S. Barnett and A. Madan, retrieved from the Internet on July 29, 2002, < http://physicsweb.org/box/world/11/1/11/world-11-1-11-1 >. ✓	

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